Notice of References Cited

Application/Control No. 10/808,499	Reexaminatio	Applicant(s)/Patent Under Reexamination MIYAIRI ET AL.		
Examiner	Art Unit			
Jeffrey R. West	2857	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,975,386	12-2005	Tsumura et al.	356/30
*	В	US-6,647,148	11-2003	Ozawa et al.	382/199
*	С	US-2005/0041226	02-2005	Tanaka et al.	355/053
*	D	US-2004/0228526	11-2004	Lin et al.	382/165
*	Е	US-6,861,614	03-2005	Tanabe et al.	219/121.66
*	F	US-2003/0142298	07-2003	Ujihara et al.	356/237.2
*	G	US-5,835,614	11-1998	Aoyama et al.	382/104
*	Н	US-5,091,963	02-1992	Litt et al.	382/149
*	Т	US-6,836,532	12-2004	Durst et al.	378/73
	J	US-			
	к	US-			
	L	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2000114174A-Translated	04-2000	Japan	ABE, HIROYUKI	H01L 21/20
	0	JP2000031229 A-Translated	01-2000	Japan	TERADA, SHIGEKI	G01J 3/42
	Р	JP2002217107A-Translated	08-2002	Japan	WADA et al.	H01L 21/66
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	manada apprimina (accept acce		
	٧			
	w			
	×			

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.